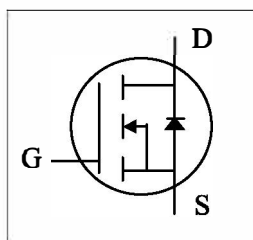


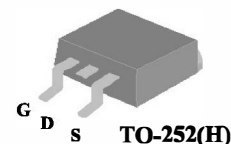
AP10N10K

N-Channel Power MOSFET

- ▼ 100% R_g & UIS Test
- ▼ Simple Drive Requirement
- ▼ Fast Switching Characteristic
- ▼ RoHS Compliant & Halogen-Free



BV_{DSS}	100V
$R_{DS(ON)}$	135mΩ
I_D	10A



Description

AP10N10K series are from Advanced Power innovated design and silicon process technology to achieve the lowest possible on-resistance and fast switching performance. It provides the designer with an extreme efficient device for use in a wide range of power applications.

The TO-252 package is widely preferred for all commercial-industrial surface mount applications using infrared reflow technique and suited for high current application due to the low connection resistance.

Absolute Maximum Ratings@T_j=25°C(unless otherwise specified)

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	100	V
V_{GS}	Gate-Source Voltage	+20	V
$I_D@T_C=25^\circ C$	Drain Current, V_{GS} @ 10V	8.1	A
$I_D@T_C=100^\circ C$	Drain Current, V_{GS} @ 10V	5.1	A
I_{DM}	Pulsed Drain Current ¹	28	A
$P_D@T_C=25^\circ C$	Total Power Dissipation	20.8	W
$P_D@T_A=25^\circ C$	Total Power Dissipation ³	2	W
E_{AS}	Single Pulse Avalanche Energy ⁴	8	mJ
T_{STG}	Storage Temperature Range	-55 to 150	°C
T_J	Operating Junction Temperature Range	-55 to 150	°C

Thermal Data

Symbol	Parameter	Value	Units
Rthj-c	Maximum Thermal Resistance, Junction-case	6	°C/W
Rthj-a	Maximum Thermal Resistance, Junction-ambient (PCB mount) ³	62.5	°C/W

AP10N10K

N-Channel Power MOSFET

Electrical Characteristics@T_j=25°C(unless otherwise specified)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V, I _D =250μA	100	-	-	V
R _{DS(ON)}	Static Drain-Source On-Resistance ²	V _{GS} =10V, I _D =5A	-	-	135	mΩ
		V _{GS} =4.5V, I _D =3A	-	-	145	mΩ
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D =250μA	1	-	3	V
g _{fs}	Forward Transconductance	V _{DS} =10V, I _D =5A	-	17	-	S
I _{DSS}	Drain-Source Leakage Current	V _{DS} =80V, V _{GS} =0V	-	-	25	μA
I _{GSS}	Gate-Source Leakage	V _{GS} = ±20V, V _{DS} =0V	-	-	+100	nA
Q _g	Total Gate Charge	I _D =5A	-	11	17.6	nC
Q _{gs}	Gate-Source Charge	V _{DS} =80V	-	2	-	nC
Q _{gd}	Gate-Drain ("Miller") Charge	V _{GS} =10V	-	-	-	nC
t _{d(on)}	Turn-on Delay Time	V _{DS} =50V	-	6	-	ns
t _r	Rise Time	I _D =5A	-	8	-	ns
t _{d(off)}	Turn-off Delay Time	R _G =3.3Ω	-	4	-	ns
t _f	Fall Time	V _{GS} =10V	-	3	-	ns
C _{iss}	Input Capacitance	V _{GS} =0V	-	580	928	pF
C _{oss}	Output Capacitance	V _{DS} =50V	-	27	-	pF
C _{rss}	Reverse Transfer Capacitance	f=1.0MHz	-	19	-	pF
R _g	Gate Resistance	f=1.0MHz	-	2	4	Ω

Source-Drain Diode

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
V _{SD}	Forward On Voltage ²	I _S =5A, V _{GS} =0V	-	-	1.3	V
t _{rr}	Reverse Recovery Time	I _S =5A, V _{GS} =0V,	-	20	-	ns
Q _{rr}	Reverse Recovery Charge	di/dt=100A/μs	-	18	-	nC

Notes:

- 1.Pulse width limited by Max. junction temperature.
- 2.Pulse test
- 3.Surface mounted on 1 in² copper pad of FR4 board
- 4.Starting T_j=25°C , V_{DD}=50V , L=1mH , R_G=25Ω

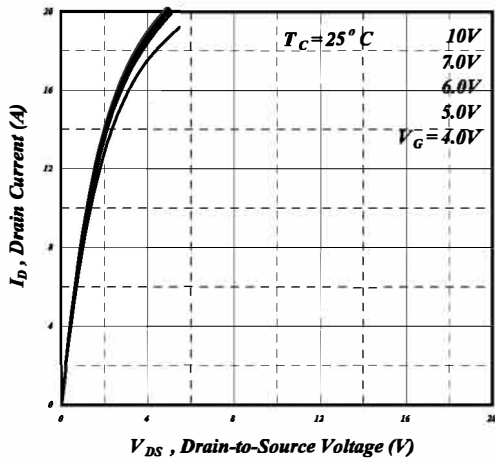


Fig 1. Typical Output Characteristics

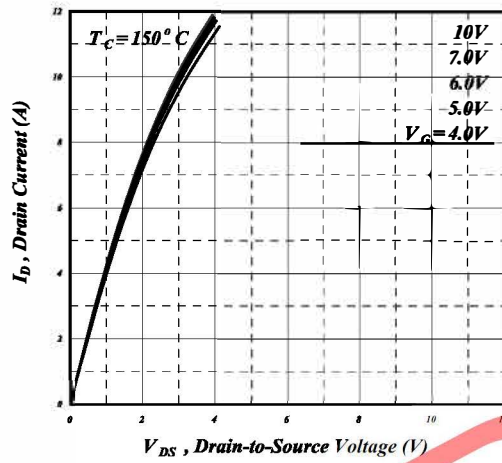


Fig 2. Typical Output Characteristics

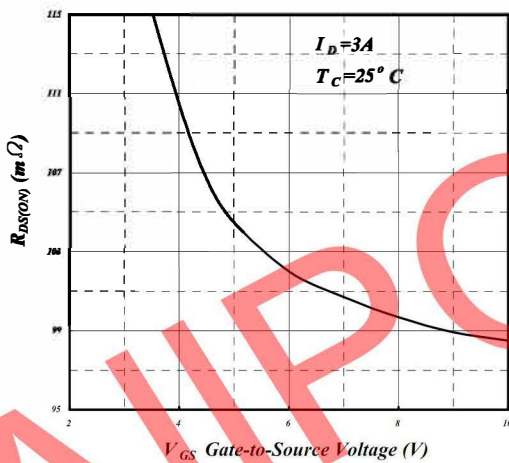


Fig 3. On-Resistance v.s. Gate Voltage

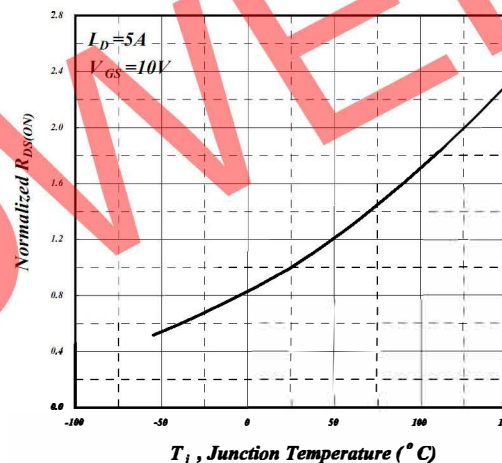


Fig 4. Normalized On-Resistance v.s. Junction Temperature

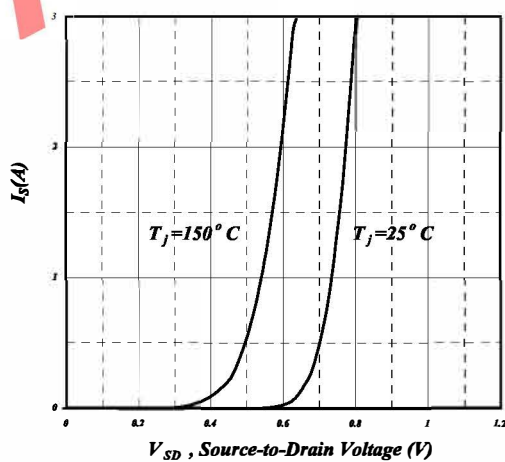


Fig 5. Forward Characteristic of Reverse Diode

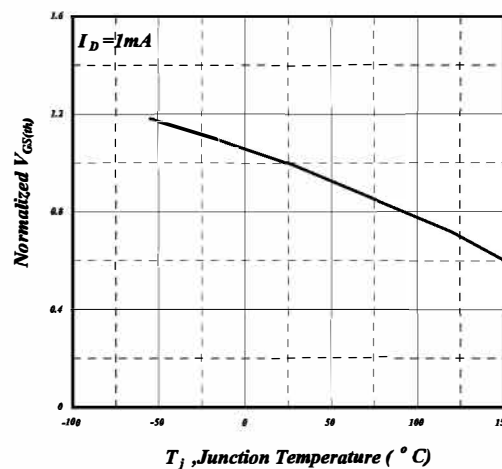


Fig 6. Gate Threshold Voltage v.s. Junction Temperature

AP10N10K
N-Channel Power MOSFET

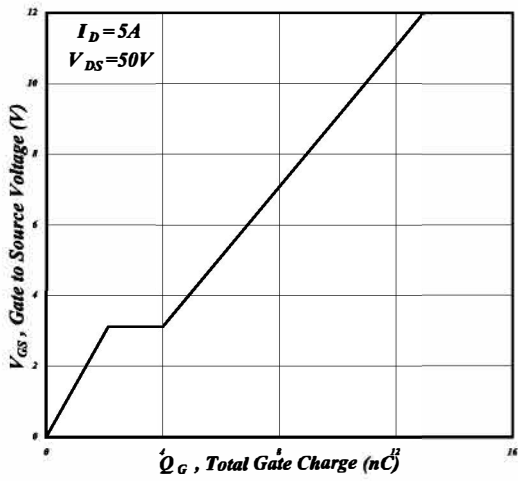


Fig 7. Gate Charge Characteristics

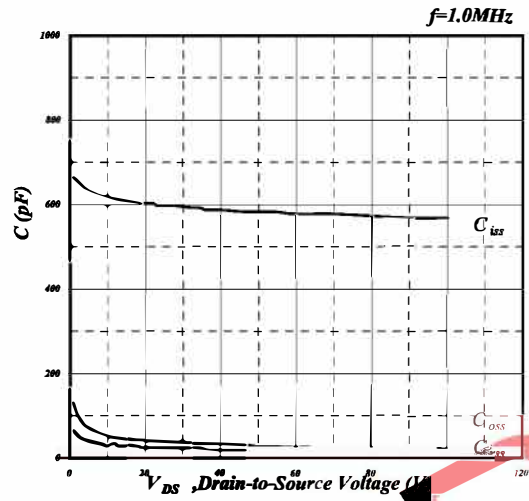


Fig 8. Typical Capacitance Characteristics

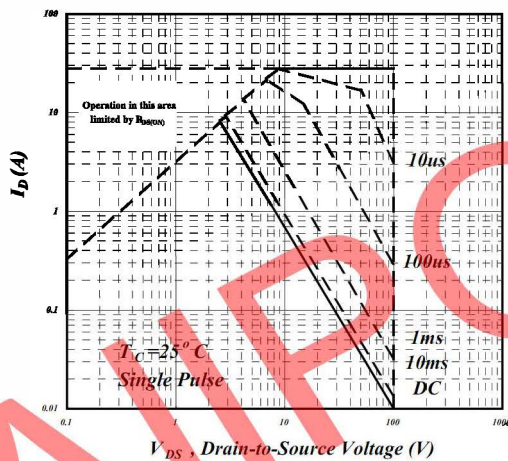


Fig 9. Maximum Safe Operating Area

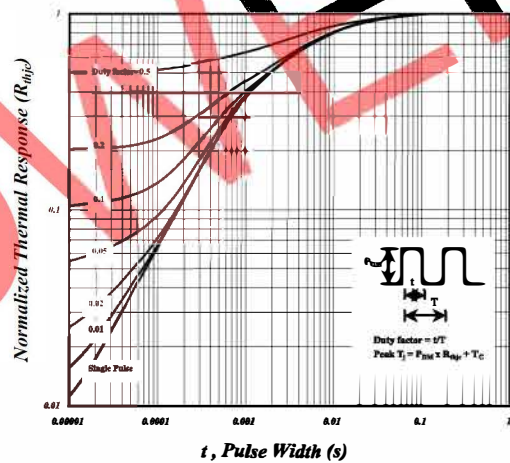


Fig 10. Effective Transient Thermal Impedance

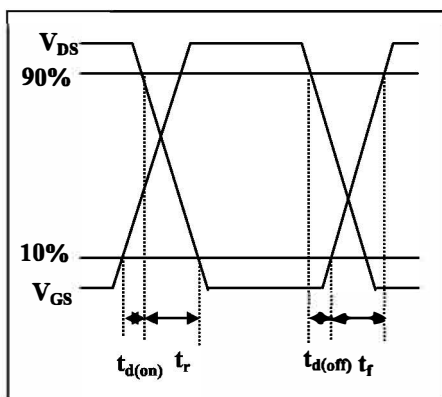


Fig 11. Switching Time Waveform

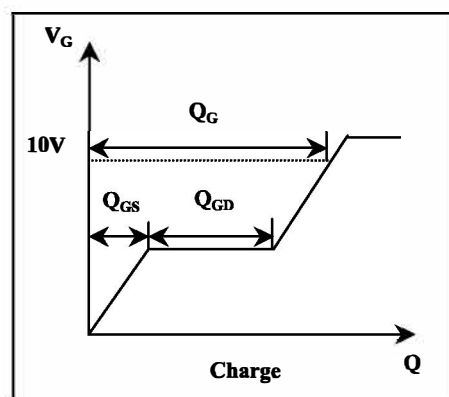


Fig 12. Gate Charge Waveform

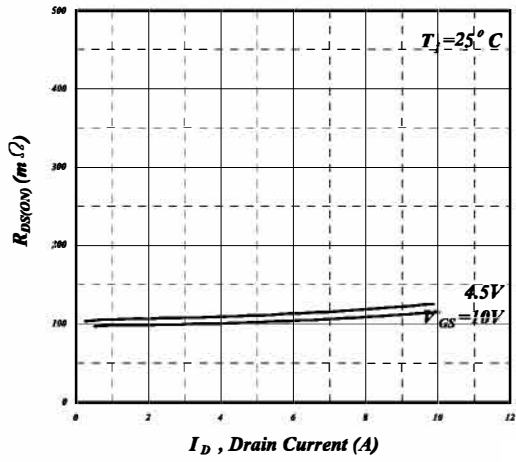


Fig 13. Typ. Drain-Source on State Resistance

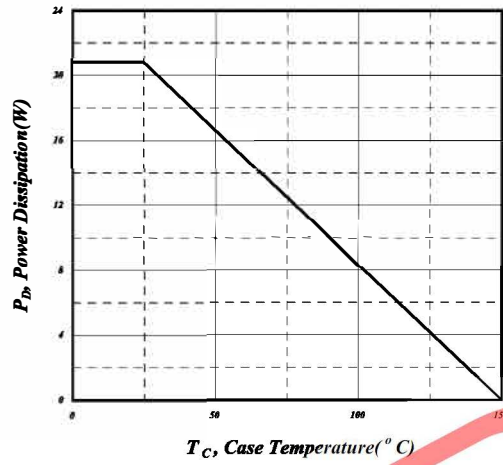


Fig 14. Total Power Dissipation

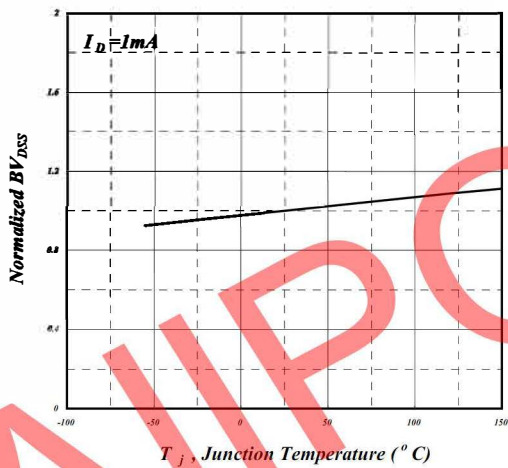
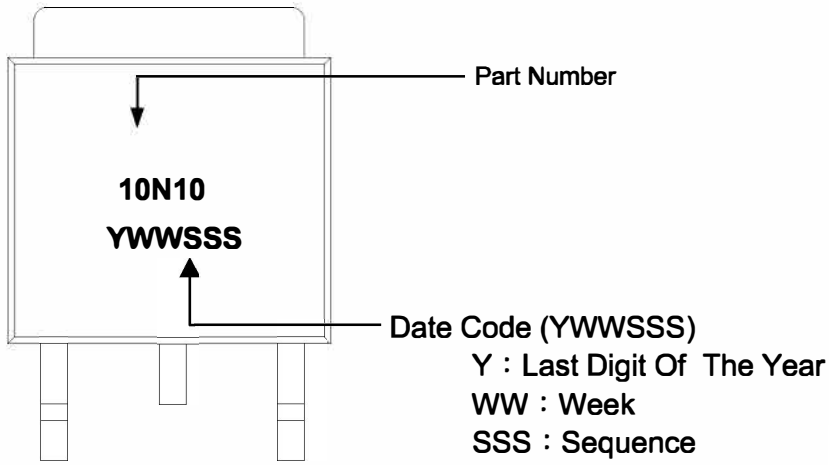


Fig 15. Normalized BV_{DSS} v.s. Junction

MARKING INFORMATION



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